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General Multilayer Ceramic Capacitors



MLCC is an electronic part that temporarily stores an electrical charge and the most prevalent type of capacitor today. New technologies have enabled the MLCC manufacturers to follow the trend dictated by smaller and smaller electronic devices such as Cellular telephones, Computers, DSC, DVC

General Features

- Miniature Size
- Wide Capacitance and Voltage Range
- Tape & Reel for Surface Mount Assembly
- Low ESR

Applications

- General Electronic Circuit

Part Numbering

CL	<u> 10</u>	<u>B</u>	<u>104</u>	K	<u>B</u>	<u>8</u>	N	N	N	<u>C</u>
	2	8		[5	[6		8	9		

- ☐ Samsung Multilayer Ceramic Capacitor
- ☐ Size(mm)
- ☐ Capacitance Temperature Characteristic
- □ Nominal Capacitance
- □ Capacitance Tolerance
- ☐ Rated Voltage

- ☐ Thickness Option
- ☐ Product & Plating Method
- □ Samsung Control Code
- Reserved For Future Use
- Packaging Type
- ☐ Samsung Multilayer Ceramic Capacitor

☐ SIZE(mm)

Code	EIA CODE	Size(mm)
03	0201	0.6 🛘 0.3
05	0402	1.0 🛘 0.5
10	0603	1.6 🛘 0.8
21	0805	2.0 🛘 1.25
31	1206	3.2 🛘 1.6
32	1210	3.2 🛘 2.5
43	1812	4.5 🛘 3.2
55	2220	5.7 🛘 5.0





☐ CAPACITANCE TEMPERATURE CHARACTERISTIC

Code		Temperature Range			
С		COG	СП	0 □ 30(ppm/ □)	
Р		P2H	P 🛭	-150 🛘 60	
R		R2H	R 🛭	-220 🛘 60	
S	Class 🛘	S2H	S□	-330 □ 60	-55 ~ +125
Т		T2H	T 🛭	-470 □ 60	
U		U2J	UΠ	-750 🛘 60	
L		S2L	S□	+350 ~ -1000	
Α		X5R	X5R	□ 15%	-55 ~ +85 □
В	Class 🛘	X7R	X7R	□ 15%	-55 ~ +125 □
Х	J Class II	X6S	X6S	□ 22%	-55 ~ +105 ^[]
F		Y5V	Y5V	+22 ~ -82%	-30 ~ +85 □

□ Temperature Characteristic

Temperature Characteristics	Below 2.0pF	2.2 ~ 3.9pF	Above 4.0pF	Above 10pF
СП	C0G	C0G	C0G	C0G
P 🛘	-	P2J	P2H	P2H
R 🛮	-	R2J	R2H	R2H
SI	-	S2J	S2H	S2H
T D	-	T2J	T2H	T2H
U	-	U2J	U2J	U2J

 $\mathsf{J}:\, \square 120\mathsf{PPM}/\,\square\,,\, \mathsf{H}:\, \square 60\mathsf{PPM}/\,\square\,,\, \mathsf{G}:\, \square 30\mathsf{PPM}/\,\square$

☐ NOMINAL CAPACITANCE

Nominal capacitance is identified by 3 digits.

The first and second digits identify the first and second significant figures of the capacitance.

The third digit identifies the multiplier. 'R' identifies a decimal point.

□ Example

Code	Nominal Capacitance
1R5	1.5pF
103	10,000pF, 10nF, 0.01 □ F
104	100,000pF, 100nF, 0.1 ☐ F





☐ CAPACITANCE TOLERANCE

Code	Tolerance	Nominal Capacitance
Α	□0.05pF	
В	□ 0.1pF	
С	□ 0.25pF	Less than 10pF (Including 10pF)
D	□ 0.5pF	(motioning Topi)
F	□1pF	
F	□1%	
G	□2%	
J	□5%	More than 10pF
K	□ 10%	More than 10pF
М	□20%	
Z	+80, -20%	

☐ RATED VOLTAGE

Code	Rated Voltage	Code	Rated Voltage
R	4.0 V	D	200 V
Q	6.3V	E	250 V
P	10V	G	500 V
O	16V	Н	630 V
Α	25V	I	1,000V
L	35V	J	2,000V
В	50V	К	3,000V
С	100V		





☐ THICKNESS OPTION

Size	Code	Thickness(T)	Size	Code	Thickness(T)
0201(0603)	3	0.30 🗆 0.03		F	1.25 🗆 0.20
0402(1005)	5	0.50 □0.05		н	1.6 🛮 0.20
0603(1608)	8	0.80 □0.10	1812(4532)	I	2.0 🛮 0.20
	Α	0.65 □0.10		J	2.5 🛮 0.20
0005(0010)	С	0.85 □0.10		L	3.2 🛮 0.30
0805(2012)	F	1.25 🛮 0.10		F	1.25 🗆 0.20
	Q	1.25 🛮 0.15		Н	1.6 🛮 0.20
	С	0.85 □0.15	2220(5750)	I	2.0 🛮 0.20
1206(3216)	F	1.25 🛮 0.15		J	2.5 🛮 0.20
	Н	1.6 🗆 0.20		L	3.2 □0.30
	F	1.25 🛮 0.20			
	Н	1.6 □0.20			
1210(3225)	I	2.0 □0.20			
	J	2.5 🗆 0.20			
	V	2.5 □0.30			

☐ PRODUCT & PLATING METHOD

Code	Electrode	Termination	Plating Type
Α	Pd	Ag	Sn_100%
N	Ni	Cu	Sn_100%
G	Cu	Cu	Sn_100%

☐ SAMSUNG CONTROL CODE

Code	Description of the code	Code	Description of the code
Α	Array (2-element)	N	Normal
В	Array (4-element)	Р	Automotive
С	High - Q	L	LICC





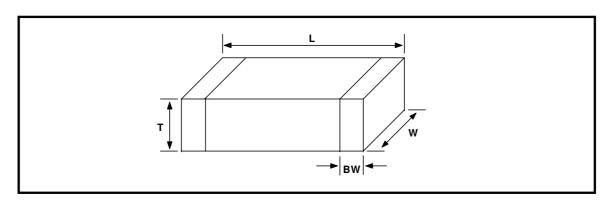
☐ RESERVED FOR FUTURE USE

Code	Description of the code
N	Reserved for future use

☐ PACKAGING TYPE

Code	Packaging Type	Code	Packaging Type
В	Bulk	F	Embossing 13" (10,000EA)
Р	Bulk Case	L	Paper 13" (15,000EA)
С	Paper 7"	0	Paper 10"
D	Paper 13" (10,000EA)	S	Embossing 10"
E	Embossing 7"		

APPEARANCE AND DIMENSION



CODE	EIA CODE	DIMENSION (mm)							
CODE	EIA CODE	L	w	T (MAX)	BW				
03	0201	0.6 🛮 0.03	0.3 🛘 0.03	0.33	0.15 🛮 0.05				
05	0402	1.0 🛮 0.05	0.5 🛮 0.05	0.55	0.2 +0.15/-0.1				
10	0603	1.6 🛮 0.1	0.8 🛘 0.1	0.9	0.3 🛮 0.2				
21	0805	2.0 🛮 0.1	1.25 🛮 0.1	1.35	0.5 +0.2/-0.3				
04	1000	3.2 🛮 0.15	1.6 🛭 0.15	1.40	0.5 +0.2/-0.3				
31	1206	3.2 🛮 0.2	1.6 🛘 0.2	1.8	0.5 +0.3/-0.3				
32	1210	3.2 🛮 0.3	2.5 🛮 0.2	2.7	06 002				
32	1210	3.2 🛘 0.4	2.5 🛮 0.3	2.8	0.6 🗆 0.3				
43	1812	4.5 🛘 0.4	3.2 🛘 0.3	3.5	0.8 🛘 0.3				
55	2220	5.7 🛭 0.4	5.0 🛘 0.4	3.5	1.0 🛘 0.3				





NO	ITE	М	PER	FORMANCE	TEST	CONDITION							
1	Appea	rance	No Abnormal Exterior	Appearance	Through Microscope(×10)							
2	Insula Resist		10,000MΩ or 500MΩ·μF Rated Voltage is below 10,000MΩ or 100MΩ·μF	w 16V ;	Apply the Rated Voltage For 60 ~ 120 Sec.								
3	Withsta Volta	•	No Dielectric Breakdov Mechanical Breakdowr		Class : 300% of the Rated Voltage for 1~5 sec. Class : 250% of the Rated Voltage for 1~5 sec. is applied with less than 50mA current								
					Capacitance	Frequency	Voltage						
		Class	Within the specifie	ed tolerance	□ 1,000 pF	1MHz ±1 0%	25 5 1/						
	Capacita				>1,000 pF	1kHz ±1 0%	0.5 ~ 5 Vrms						
4	nce				Capacitance	Frequency	Voltage						
		Class	Within the specifi	ied tolerance	□ 10 μF	1kHz ±1 0%	1.0±0.2Vrms						
				>1 0 µF	120Hz±20%	0.5±0.1 Vrms							
			Capacitance [] 30pF :	: Q □1.000	Capacitance	Frequency	Voltage						
5	Q	Class	SS < 30pF: Q □ 400 +20C		□ 1,000 pF	1MHz ±1 0%							
			(C	C : Capacitance)	>1,000 pF	1kHz ±1 0%	0.5 ~ 5 Vrms						
			1. Characteristic : A()	X5R), B(X7R), X(X6S)	Capacitance	Frequency	Voltage						
									Rated Voltage	Spec	□ 10 μF	1kHz ±1 0%	1.0±0.2Vrms
			25V	0.025 max	>1 0 μF	120Hz±20%	0.5±0.1 Vrms						
			16V	0.035 max									
			10V	0.05 max	-								
			6.3V	0.05 max/ 0.10max*1	*1. 0201 C □ 0.022uF, 0	402 C □0.22uF, 0603 C □2.2ul							
							2. Characteristic : F(Y5V)	0805 C □4.7uF, 1206 C □10uF, 1210 C □22uF, 1812 C □47uF, 2220 C □100uF, All Low Profile Capacitors (P.16).				
6	Tan 🛭	Class	Rated Voltage	Spec	*2 0603 C \(\text{0.47uF}, 08 \\ \text{1.3. 0402 C \(\text{0.033uF}, 06 \\ \text{0.033uF}, \text{0.0603} \)								
			50V	0.05 max, 0.07max*2	All 0805, 1206 size		F						
			35V	0.07 max	*4 1210 C>6.8uF	,							
			25V	0.05 max/ 0.07 max* ³ / 0.09max* ⁴	*5 0402 C 0.22uF *6 All 1812 size								
			16V	0.09 max/ 0.125max*5	0 All 1012 Size								
			10V	0.125 max/ 0.16max*6	1								
			6.3V	0.16max									





NO	ITE	M	PERFORMANCE			TEST CONDITION			
						Capacitance s	shall be measured by the steps		
					T 0 ": :		following table.		
			Characte	ristics	Temp. Coefficient (PPM/□)	Step	Temp.(□)		
			COG	+	0 ± 30	1 3tep	25 ± 2		
			PH		-150 ± 60	2			
		Class	RH		-220 ± 60	1	Min. operating temp. ± 2		
			SH		-330 ± 60	3	25 ± 2		
			TH		-470 ± 60	4	Max. operating temp ± 2		
			UL		-750 ± 120	5	25 ± 2		
				SL		+350 ~ -1000	(1) Class 🛚		
							Coefficient shall be calculated from		
7	Temperature					the formula a			
7	Characteristics of Capacitance					Temp, Coefficie	$nt = \frac{C2 - C1}{C1 \times \Box T} \Box 10^6 \Box ppm \angle \Box \Box$		
						C1; Capacita	ance at step 3		
			Oh a va ata		Capacitance Change	C2: Capacita	ance at 85 []		
			Characte	eristics	Capacitance Change with No Bias	□ T: 60 □ (=8	35 🛮 -25 🗓)		
		Class	A(X5 B(X7	R)/ 'R)	±15%	(2) CLASS []			
		Ц	X(X6	(S)	±22%	Capacitance Change shall be calculated from t			
			F(Y5	V)	+22% ~ -82%	formula as be	elow.		
			<u> </u>	· I		□C = <u>C2 -</u>	<u>C1</u>		
							ance at step 3		
							ance at step 2 or 4		
							* Pressure for 10±1 sec.		
							201 case size.		
	Adhesive	Strength	No Indicati	on Of Pee	ling Shall Occur On The				
8	of Termi	ination	Terminal E	lectrode.			F00 x f		
							500g.f		
						Bending limit	: 1mm		
		Apperance	No mecha	ınical dam	nage shall occur.	Test speed;			
			Ch	o vioti	Conceitante	-	board at the limit point in 5 sec.,		
			Charact	eristics	Capacitance Change	Then measure	e capacitance.		
					Within ±5% or ± 0.5				
			Clas	s I	pF whichever is		20		
					larger		R=340*		
9	9 Bending Strength				1 3 2	50			
		Capacitance		A(X5R)/		7	▲		
		Capacitarios		B(X7R)/	Within ±12.5%				
				X(X6S)		ا	T		
			Class II			45±1	Bending limit 45±1		
				F(Y5V)	Within ±30%	B=230 For	0201 Case size		
				1 (134)	-VICINI 100/6	1	<u> </u>		
			1		1				





NO	IT	ЕМ		PERF	ORMANCE	TEST CONDITION			
			More Than	n 95% of th	ne terminal surface is to	Solder	Sn-3Ag-0.5	Cu 63Sn-37Pb	
			be soldere	ed newly, So	o metal part does not	Solder	-		
			come out	or dissolve		Temp.	245±5 🛚	235±5 🏻	
10	Solde	erability				Flux	R	МА Туре	
						Dip Time	3±0.3 sec	5±0.5 sec.	
						Pre-heatin	g at 80~120	☐ for 10~30 sec.	
		Apperance	No mecha	anical dam	age shall occur.	Solder Ten	nperature: 270	±5 🛮	
			Charac	teristics	Capacitance Change	Dip Time :			
					Within ±2.5% or	preheated		fully immersed and	
				ss 🛘	±0.25pF whichever is	premeated	as below .		
		Capacitance		A OVERN	larger	STEP	TEMP.(□)	TIME(SEC.)	
				A(X5R)/ B(X7R)	Within ±7.5%	1	80~100	60	
			Class []	X(X6S)	Within ±15%	2	150~180	60	
	Resistance to			F	Within ±20%	Leave the	canacitor in an	nbient condition for	
11	Soldering heat		Capacitar	Capacitance 30pF : Q 1000			me* before me:		
		Q (Olara 🗇)		<30 pF	: Q □ 400+20×C	* 24 ± 2 h	ours (Class 0))	
		(Class 🛘)			(C: Capacitance)	48 ± 4 h	ours (Class [)	
		Tan 🛮	Within the	e specified	initial value				
		(Class 🛘)	VVIIIIII LIIC	Specified	initial value				
		Insulation	Within the	e specified	initial value				
		Resistance	·						
		Withstanding Voltage	Within the specified initial value						
		Vollago							
		Appearance	No mecha	anical dam	age shall occur.				
			Charact	teristics	Capacitance Change	1			
					Within ±2.5% or		tor shall be su	•	
			Clas	ss 🛘	±0.25pF whichever is		_	a total amplitude of y from 10Hz to 55Hz	
		Capacitance		1	larger		o 10Hz In 1 m		
		·		A(X5R)/ B(X7R)	Within ±5%				
12	Vibration		Class	X(X6S)	Within ±10%	Repeat this	for 2hours ea	ch in 3 mutually	
	Test			F(Y5V)	Within ±20%	perpendicu	perpendicular directions		
		Q			I	1			
		(Class 🛘)		e specified	initial value				
		Tan 🛚	\\/ithin th	onosifis -	initial value	Î			
		(Class 🛘)	vviunin the	s specified	initial value				
		Insulation	Within the specified initial value						
		Resistance	vvitnin the	e specified	initial value				





NO	ITE	M		PERFO	RMANCE	TEST CONDITION			
		Appearance	No mechanic	al damage sha	Il occur.	Temperature : 40±2 □			
				cteristics	Capacitance Change	Relative humidity: 90~95 %RH			
			Ullara	0101101100	<u> </u>	Duration time : 500 +12/-0 hr.			
			Cla	ss 🛚	Within ±5.0% or ±0.5pF	23333 4			
		Capacitance		I	whichever is larger	Leave the capacitor in ambient			
				A(X5R)/		condition for specified time* before			
			Class	B(X7R)/	Within ±12.5%	measurement.			
				X(X6S)		CLASS : 24±2 Hr.			
				F(Y5V)	Within ±30%	CLASS : 48±4 Hr.			
			Capacitance	□ 30pF : Q □	350	GEAGGE : IGET III.			
	Humidity	Q	10 🛭 Capacit	tance <30pF : C	Q □ 275 + 2.5×C				
13	(Steady	CLASS	Capacitance	< 10pF : Q 🛭 3	200 + 10×C (C: Capacitance)				
	State)		1. Characteri	stic: A(X5R),	2. Characteristic : F(Y5V)	1			
			B(X7R)						
			0.05max (16V and over)		0.075max (25V and over)				
		Tan 🛮	0.075max (10	OV)	0.1max (16V, C<1.0μF)				
		CLASS [0.075max		0.125max(16V, C □ 1.0 µF)				
			(6.3V excep	t Table 1)	0.15max (10V)				
			0.125max*		0.195max (6.3V)				
			(refer to Tab	le 1)					
						-			
		Insulation	1,000 MΩ or	50MΩ·μF whiche	ver is smaller.				
		Resistance							
		Appearance	No mechanic	al damage sha	Applied Voltage : rated voltage				
			Chara	cteristics	Capacitance Change	Temperature : 40±2 □			
					Within ±5.0% or ±0.5pF	- Humidity::90~95%RH Duration Time:500 +12/-0 Hr.			
			Cla	ss 🛘	whichever is larger	Charge/Discharge Current : 50mA max.			
				A(X5R)/	Within ±12.5%	-			
		Capacitance		B(X7R)/	Within ±12.5%	Perform the initial measurement according to			
				X(X6S)	Within ±30%	Note1.			
			Class II	11(112)		-			
			Class		Within ±30%	-			
				F(Y5V)	Within +30~ - 40%	Perform the final measurement according to			
					In case of Table 2 *	Note2.			
	Moisture	Q	Capacitance	□ 30pF : Q □ 2	200				
14	Resistance	(Class [])		•	00 + 10/3×C (C: Capacitance)				
		,							
			1. Characteri	stic : A(X5R),	2. Characteristic : F(Y5V)				
				B(X7R)					
			0.05max (16\	,	0.075max (25V and over)				
			0.075max (10	JV)	0.1max (16V, C<1.0μF)				
		Tan 🛮	0.075max		0.125max(16V, C \(\text{1.0 μF} \)				
		(Class [])	(6.3V excep	t Table 1)	0.15max (10V)				
			0.125max*		0.195max (6.3V)				
			(refer to Tal	ble 1)					
			X(X6S) 0.11r	nax (6.3V and I	below)				
		Insulation				-			
		Resistance	500 MΩ or 25	δ MΩ· μ F whicheve	r is smaller.				





NO	ITE	М		PER	FORMANCE		TEST CONDIT	ION		
		Appearance	No mechanio	cal damage	shall occur.	1	oltage: 200%* of the	=		
			Charact	eristics	Capacitance Change		ime: 1000 +48/-0 H			
			Class		Within ±3% or ±0.3pF,	Charge/Dis	charge Current: 50n	nA max.		
			Class	· ·	Whichever is larger	* refer to table(3): 150%/100% of the rated				
		Capacitance		A(X5R)/ B(X7R)	Within ±12.5%	voltage	voltage			
			Class 🛘	X(X6S)	Within ±25%	Perform the	e initial measuremen	according to		
			Olass I		Within ±30%	Note1 for	Class [
				F(Y5V)	Within +30~ - 40%					
					* In case of Table 2	Perform the	e final measurement	according to		
		Q	Capacitance	-		Note2.				
		(Class [])		•	F : Q 🛘 275 + 2.5×C					
45	High		Capacitance Character		200 +10×C (C: Capacitance)	-				
15	Temperature Resistance		Gridianio	B(X7R)	.					
	nesistance		0.05max	,	0.075max					
			(16V and o	ver)	(25V and over)					
			0.075max (1	0V)	0.1max(16V, C<1.0μF)					
		Tan □	0.075max		0.125max(16V, C □ 1.0 <i>μ</i> F)					
		(Class [])	(6.3V except	ot Table 1)	0.15max (10V)					
			0.125max*		0.195max (6.3V)					
			(refer to Ta	ble 1)						
			X(X6S) 0.11	max (6.3V a	nd below)					
		Insulation Resistance	1,000 MΩ or	50MΩ·μF whic	chever is smaller.					
		Appearance	No mechania	cal damage	shall occur.	Capacitor	shall be subjecte	d to 5 cycles.		
			Charact	eristics	Capacitance Change	Condition	for 1 cycle :			
			Class	. п	Within ±2.5% or ±0.25pF	Step	Temp.(□)	Time(min.)		
		Capacitance	Olass	A(X5R)/	Whichever is larger	1	Min. operating temp.+0/-3	30		
		Capacitario	Class	B(X7R)/	Within ±7.5%	2	25	2~3		
16	Temperature			X(X6S)	Within ±15%	3	Max. operating	30		
	Cycle			F(Y5V)	Within ±20%	1	temp.+3/-0			
		Q	Within the s	pecified initia	al value	4	25	2~3		
		(Class [])				+	e capacitor in amb			
		Tan 🛚	Within the s	pecified initia	al value	1	ied time* before m	neasurement		
		(Class 🛘)				* 24 ± 2 hours (Class [])				
		Insulation	Within the s	pecified initia	al value	48 ± 4	hours (Class [])			
		Resistance								





		Reco	ommended Sold	ering Method		
		Size	Temperature		Cond	lition
		inch (mm)	Characteristic	Capacitance	Flow	Reflow
		0201 (0603)	-	-	-	
		0402 (1005)				
			Class I	-		
		0603 (1608)	Class II	C < 1μF		
			Class II	C 🛭 1μF	-	
	Recommended	0805 (2012)	Class I	-		
18	Soldering Method		Class II	C < 4.7μF		
	By Size & Capacitance		Olass II	C 🛮 4.7μF	-	
	by ones a supusitation		Array	-	-	
			Class I	-		
		1006 (2016)	Class II	C < 10μF		
		1206 (3216)	Class II	C 🛭 10 <i>μ</i> F	-	
			Array	-	-	
		1210 (3225)				
		1808 (4520)				
		1812 (4532)	-	-	-	
		2220 (5750)				

Note1. Initial Measurement For Class [

Perform the heat treatment at $150 \, \square + 0/-10 \, \square$ for 1 hour. Then Leave the capacitor in ambient condition for 48 ± 4 hours before measurement. Then perform the measurement.

Note2. Latter Measurement

1. CLASS 🛚

Leave the capacitor in ambient condition for 24±2 hours before measurement

Then perform the measurement.

2. Class 🛘

Perform the heat treatment at $150 \, \square + 0/-10 \, \square$ for 1 hour. Then Leave the capacitor in ambient condition for 48 ± 4 hours before measurement. Then perform the measurement.

*Table1.

Tan 🛮	0.125max*
Class □ A(X5R), B(X7R)	0201 C □ 0.022μF 0402 C □ 0.22μF 0603 C □ 2.2μF 0805 C □ 4.7μF 1206 C □ 10.0μF 1210 C □ 22.0μF 1812 C □ 47.0μF 2220 C □ 100.0μF All Low Profile Capacitors (P.16).

*Table2.

High Tem	High Temperature Resistance test							
□C (Y5V)	+30~ - 40%							
	0402 C □ 0.47μF							
	0603 C □2.2μF							
Class∏	0805 C □4.7μF							
F(Y5V)	1206 C □10.0 <i>μ</i> F							
F(13V)	1210 C □22.0 <i>μ</i> F							
	1812 C □47.0 <i>µ</i> F							
	2220 C 🛮 100.0μF							

*Table3.

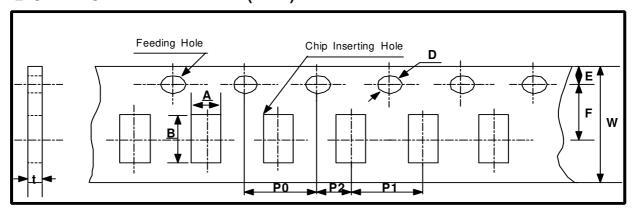
High Temperature Resistance test								
Applied Voltage	100% of the rated voltage	150% of the rated voltage						
Class A(X5R), B(X7R), X(X6S), F(Y5V)	0201 C	0201 C \Box 0.022 μ F 0402 C \Box 0.47 μ F 0603 C \Box 2.2 μ F 0805 C \Box 4.7 μ F 1206 C \Box 10.0 μ F 1210 C \Box 22.0 μ F 1812 C \Box 47.0 μ F 2220 C \Box 100.0 μ F						





PACKAGING

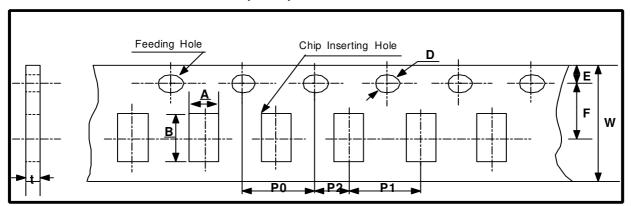
☐ CARDBOARD PAPER TAPE (4mm)



unit: mm

	ymbol ype	A	В	w	F	E	P1	P2	P0	D	t
D i m	0603 (1608)	1.1 ±0.2	1.9 ±0.2								
e n s	0805 (2012)	1.6 ±0.2	2.4 ±0.2	8.0 ±0.3	3.5 ±0.05	1.75 ±0.1	4.0 ±0.1	2.0 ±0.05	4.0 ±0.1	□1.5 +0.1/-0	1.1 Below
i o n	1206 (3216)	2.0 ±0.2	3.6 ±0.2								

☐ CARDBOARD PAPER TAPE (2mm)



unit: mm

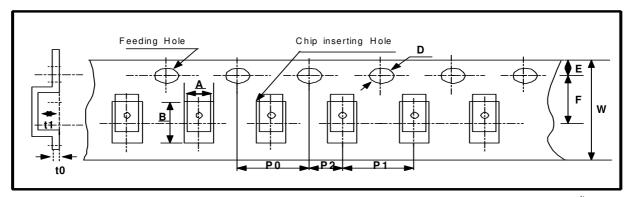
	ymbol Type	Α	В	w	F	E	P1	P2	P0	D	t
D i m e	0201 (0603)	0.38 ±0.03	0.68 ±0.03	8.0	3.5	1.75	2.0	2.0	4.0	□1.5	0.37 ±0.03
n s i o n	0402 (1005)	0.62 ±0.04	1.12 ±0.04	±0.3	±0.05	±0.1	±0.05	±0.05	±0.1	+0.1/-0.03	0.6 ±0.05





PACKAGING

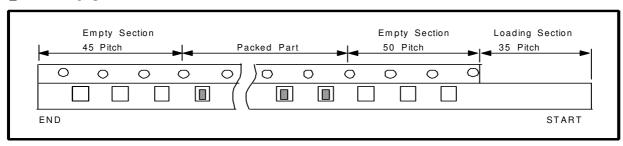
☐ EMBOSSED PLASTIC TAPE



 $u\,n\,it\,:\,m\,m$

Sy	m bol	Α	В	w	F	Е	P1	P2	P0	D	t1	t0
Т	уре	,,			·	_			. •			
	0805 (2012)	1.45 ±0.2	2.3 ±0.2									
P	1206 (3216)	1.9 ±0.2	3.5 ±0.2	8.0 ±0.3	3.5 ±0.05		4.0 ±0.1				2.5 max	
m e	1210 (3225)	2.9 ±0.2	3.7 ±0.2			1.75		2.0	4.0	□1.5 +0.1/-0		0.6
n s i	1808 (4520)	2.3 ±0.2	4.9 ±0.2			±0.1		±0.05	±0.1	+0.17-0		Below
o n	1812 (4532)	3.6 ±0.2	4.9 ±0.2	12.0 ±0.3	5.60 ±0.05		8.0 ±0.1				3.8 max	
	2220 (5750)	5.5 ±0.2	6.2 ±0.2									

□ TAPING SIZE



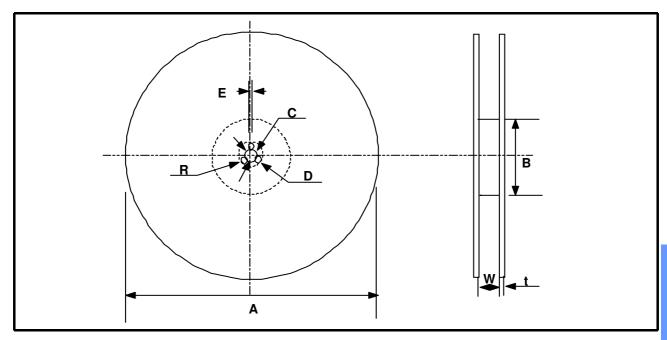
Type	Symbol	Size	Cardboard Paper Tape	Symbol	Size	Embossed Plastic Tape
		0201(0603)	10,000		All Size 3216 1210(3225),1808(4520) (t 1.6mm)	2,000
7" Reel	С	0402(1005)	10,000	E	1210(3225)(t 🛚 2.0 m m)	1,000
		OTHERS	4,000		1808(4520)(t 🗆 2.0 m m)	1,000
10" Reel	0	-	10,000	-	-	-
	D	0402(1005)	50,000		All Size 3216 1210(3225),1808(4520) (t<1.6mm)	10,000
		OTHERS	10,000		1210(3225)(1.6 🛮 t<2.0mm) 1206(3216)(1.6 🗓 t)	8,000
13" Reel		0603(1608)	10,000 or 15,000	F	1210(3225),1808(4520) (t \(2.0 \text{ m m} \)	4,000
	L	0805(2012) (t \(\Big 0.85 m m \)	15,000 or 10,000(Option)		1812(4532)(t 🛚 2.0 m m)	4,000
		1206(3216) (t \(\Pi \) 0.85mm)	10,000		1812(4532)(t>2.0mm) 5750(2220)	2,000





PACKAGING

☐ REEL DIMENSION



unit : mm

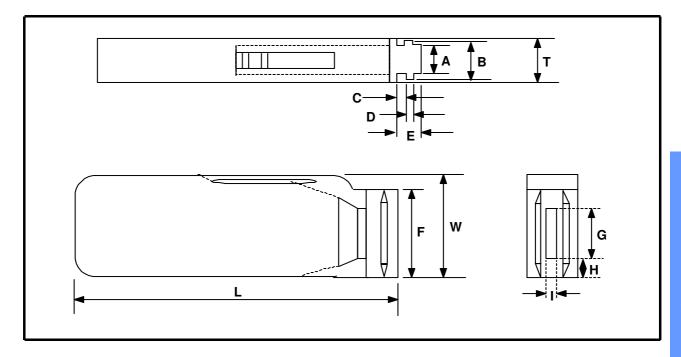
Symbol	Α	В	С	D	E	W	t	R
7" Reel	□180+0/ -3	□60+1/ -3	По По о	05 00 5	00005	0.01.5	1.2 🛮 0.2	1.0
13" Reel	□330 □2.0	□80+1/ -3	□13 □0.3	25 🛮 0.5	2.0 🗆 0.5	9 🛮 1.5	2.2 🛮 0.2	1.0





☐ BULK CASE PACKAGING

- Bulk case packaging can reduce the stock space and transportation costs.
- The bulk feeding system can increase the productivity.
- It can eliminate the components loss.



unit: mm

Symbol	Α	В	Т	С	D	E
Dimension	6.8 □0.1	8.8 🛮 0.1	12 🛮 0.1	1.5+0.1/-0	2+0/-0.1	3.0+0.2/-0

Symbol	F	W	G	Н	L	I
Dimension	31.5+0.2/-0	36+0/-0.2	19 🛮 0.35	7 🛮 0.35	110 🛮 0.7	5 □0.35

☐ QUANTITY OF BULK CASE PACKAGING

unit : pcs

Cino	0400/1005)	0602/1609\	0805(2012)
Size	0402(1005)	0603(1608)	T=0.65mm	T=0.85mm
Quantity	50,000	10,000 or 15,000	10,000	5,000 or 10,000

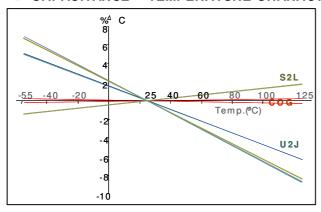


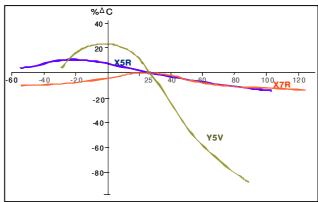


APPLICATION MANUAL

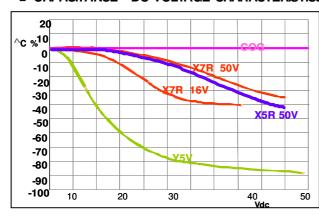
☐ ELECTRICAL CHARACTERISTICS

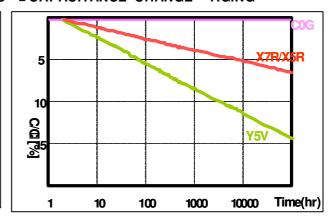
☐ CAPACITANCE - TEMPERATURE CHARACTERISTICS



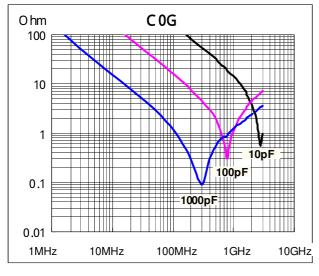


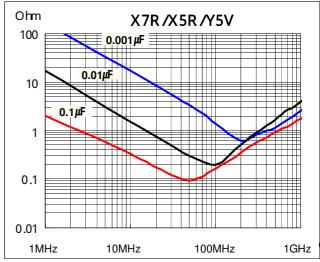
☐ CAPACITANCE - DC VOLTAGE CHARACTERISTICS ☐ CAPACITANCE CHANGE - AGING





☐ IMPEDANCE - FREQUENCY CHARACTERISTICS









□ STORAGE CONDITION

☐ Storage Environment

The electrical characteristics of MLCCs were degraded by the environment of high temperature or humidity. Therefore, the MLCCs shall be stored in the ambient temperature and the relative humidity of less than 40 \square and 70%, respectively.

Guaranteed storage period is within 6 months from the outgoing date of delivery.

□ Corrosive Gases

Since the solderability of the end termination in MLCC was degraded by a chemical atmosphere such as chlorine, acid or sulfide gases, MLCCs must be avoid from these gases.

□ Temperature Fluctuations

Since dew condensation may occur by the differences in temperature when the MLCCs are taken out of storage, it is important to maintain the temperature-controlled environment.

DESIGN OF LAND PATTERN

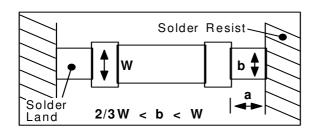
When designing printed circuit boards, the shape and size of the lands must allow for the proper amount of solder on the capacitor.

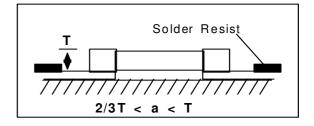
The amount of solder at the end terminations has a direct effect on the crack.

The crack in MLCC will be easily occurred by the tensile stress which was due to too much amount of solder. In contrast, if too little solder is applied, the termination strength will be insufficiently.

Use the following illustrations as guidelines for proper land design.

Recommendation of Land Shape and Size.









ADHESIVES

When flow soldering the MLCCs, apply the adhesive in accordance with the following conditions.

□ Requirements for Adhesives

They must have enough adhesion, so that, the chips will not fall off or move during the handling of the circuit board.

They must maintain their adhesive strength when exposed to soldering temperature.

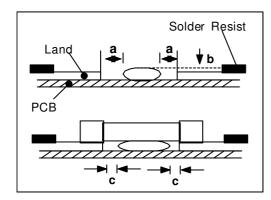
They should not spread or run when applied to the circuit board.

They should harden quickly. They should not corrode the circuit board or chip material.

They should be a good insulator. They should be non-toxic, and not produce harmful gases, nor be harmful when touched.

□ Application Method

It is important to use the proper amount of adhesive. Too little and much adhesive will cause poor adhesion and overflow into the land, respectively.



		unit : mm
Туре	21	31
а	0.2 min	0.2 min
b	70~100μm	70∼100 <i>μ</i> m
С	> 0	> 0

□ Adhesive hardening Characteristics

To prevent oxidation of the terminations, the adhesive must harden at $160 \,\Box$ or less, within 2 minutes or less.

MOUNTING

□ Mounting Head Pressure

Excessive pressure will cause crack to MLCCs. The pressure of nozzle will be 300g maximum during mounting.

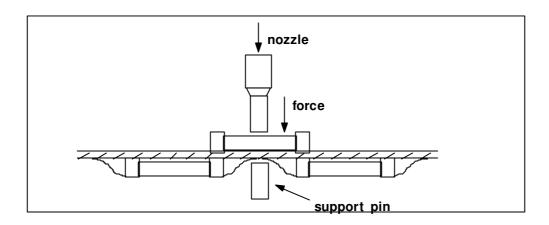




Bending Stress

When double-sided circuit boards are used, MLCCs first are mounted and soldered onto one side of the board. When the MLCCs are mounted onto the other side,

it is important to support the board as shown in the illustration. If the circuit board is not supported, the crack occur to the ready-installed MLCCs by the bending stress.



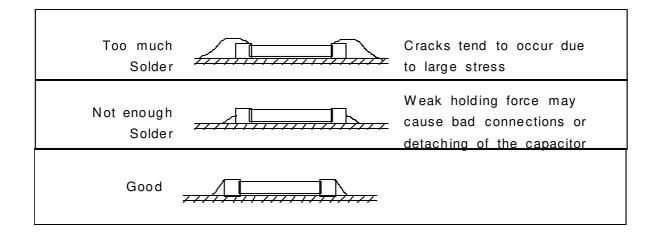
Manual Soldering

Manual soldering can pose a great risk of creating thermal cracks in chip capacitors.

The hot soldering iron tip comes into direct contact with the end terminations, and operator's carelessness may cause the tip of the soldering iron to come into direct contact with the ceramic body of the capacitor.

Therefore the soldering iron must be handled carefully, and close attention must be paid to the selection of the soldering iron tip and to temperature control of the tip.

Amount of Solder







Cooling

Natural cooling using air is recommended. If the chips are dipped into solvent for cleaning, the temperature difference (\Box T) must be less than 100 \Box

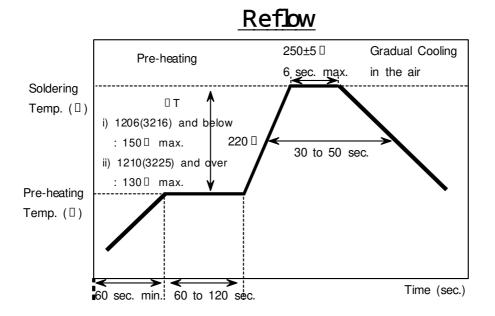
Cleaning

If rosin flux is used, cleaning usually is unnecessary. When strongly activated flux is used, chlorine in the flux may dissolve into some types of cleaning fluids, thereby affecting the chip capacitors. This means that the cleaning fluid must be carefully selected, and should always be new.

☐ Notes for Separating Multiple, Shared PC Boards.

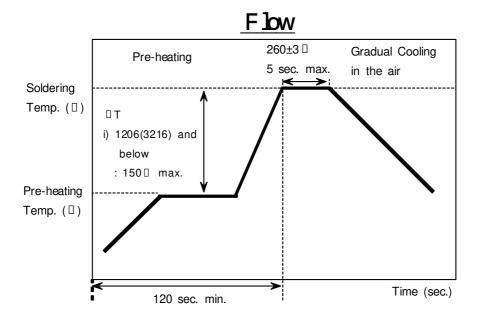
A multi-PC board is separated into many individual circuit boards after soldering has been completed. If the board is bent or distorted at the time of separation, cracks may occur in the chip capacitors. Carefully choose a separation method that minimizes the bending often circuit board.

□ Recommended Soldering Profile









Soldering Iron

Variation of Temp.	Soldering Temp (□)	Pre-heating Time (Sec)	Soldering Time(Sec)	Cooling Time(Sec)
□ T □130	300 □10 □ max	□ 60	□ 4	-

Condition of Iron facilities					
Wattage	Tip Diameter	Soldering Time			
20W Max	3mm Max	4 Sec Max			

^{*} Caution - Iron Tip Should Not Contact With Ceramic Body Directly.